L Number	Hits	Search Text	DB	Time stamp
1	2307	(("382/141-151") or ("348/87,126") or ("356/237.4,237.5")).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2001/10/02 14:07
8	24	<pre>gain near2 offset and ((("382/141-151") or ("348/87,126") or ("356/237.4,237.5")).CCLs.)</pre>	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2001/10/02 14:15
15	5	gain with offset and ((("382/141-151") or ("348/87,126") or ("356/237.4,237.5")).CCLS.) not (gain near2 offset and ((("382/141-151") or ("348/87,126") or ("356/237.4,237.5")).CCLS.))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2001/10/02 14:16
22	6	gain same offset and ((("382/141-151") or ("348/87,126") or ("356/237.4,237.5")).CCLS.) not (gain near2 offset and ((("382/141-151") or ("348/87,126") or ("356/237.4,237.5")).CCLS.)) not (gain with offset and ((("382/141-151") or ("348/87,126") or ("356/237.4,237.5")).CCLS.) not (gain near2 offset and ((("382/141-151") or ("348/87,126") or	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2001/10/02
29	4	("356/237.4,237.5")).CCLS.))) wafer with (resist or photoresist) with transparent with flat	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2001/10/02 14:22
36	177	wafer with transparent near film	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2001/10/02 14:31
43	3	("5045417").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2001/10/02 14:37
50	2	wafer near inspect\$3 with (resist or photoresist) with transparent	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2001/10/02 14:44
57	80	wafer near (film or coat\$3) with transparent	USPAT; US-PGPUB; EPO; JPO; DERWENT;	2001/10/02 14:45
64	16	(wafer near (film or coat\$3) with transparent) and inspect\$3	IBM TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;	2001/10/02 14:58
71	216	(chip near2 chip) with inspect\$3	IBM TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2001/10/02 14:58
78	142	(die near2 die) with inspect\$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2001/10/02 15:03

1 ((die near2 die) with inspect\$3) and USPAT; defect with certainty US-PGPUB EPO; JPO DERWENT; IBM TDB 92 7 ((die near2 die) with inspect\$3) and USPAT; defect with probability US-PGPUB EPO; JPO, DERWENT;	2001/10/02
92 7 ((die near2 die) with inspect\$3) and USPAT; defect with probability US-PGPUB, EPO; JPO	2001/10/02
92 7 ((die near2 die) with inspect\$3) and USPAT; US-PGPUB, EPO; JPO	2001/10/02
92 7 ((die near2 die) with inspect\$3) and USPAT; US-PGPUB, EPO; JPO,	
92 7 ((die near2 die) with inspect\$3) and USPAT; US-PGPUB, EPO; JPO,	
92 7 ((die near2 die) with inspect\$3) and USPAT; defect with probability US-PGPUB, EPO; JPO,	
defect with probability US-PGPUB, EPO; JPO,	
EPO; JPO,	15:11
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· IBM TDB	
	2007 /10 /02
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US-PGPUB;	
EPO; JPO;	
DERWENT;	
IBM TDB	
106 428 defect near probability USPAT;	2001/10/02
US-PGPUB;	15:14
EPO; JPO;	
DERWENT;	
IBM TDB	
113 15 ((("382/141-151") or ("348/87,126") or USPAT;	2001/10/02
("356/237.4,237.5")).CCLS.) and (defect US-PGPUB;	
near probability) EPO; JPO;	
DERWENT;	
IBM TDB	
120 85 defect with probability same reliability USPAT;	2001/10/02
US-PGPUB;	
EPO; JPO;	
DERWENT;	
IBM TDB	2001/10/02
distribution of the state of th	2001/10/02
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with probability) EPO; JPO;	
DERWENT;	
IBM TDB	
(((/	2001/10/02
("356/237.4,237.5")).CCLS.) and (defect US-PGPUB;	15:28
with probability) not (((("382/141-151") EPO; JPO;	
or ("348/87,126") or DERWENT;	
("356/237.4,237.5")).CCLS.) and (defect IBM TDB	
near probability))	
8 defect near classif\$6 with (probability USPAT;	2001/10/02
or certainty) US-PGPUB;	15:29
EPO; JPO;	
DERWENT;	
IBM TDB	1